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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 8554-2026

Replacing GB/T 8554-1998

**Transformers and inductors for use in electronic and
telecommunication equipment - Measuring methods and test
procedures**

电子和通信设备用变压器和电感器 测试方法和试验程序

(English Translation)

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A.3 Resistors ranging from 1ohm to several thousand ohms

A.3.1 Overview

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A.3.3 Substitution Method

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Appendix B (Normative) Dielectric Withstand Voltage Test

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